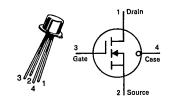
- T-37- 25

3N157 3N158

CASE 20-03, STYLE 2 TO-72 (TO-206AF)



MOSFET
AMPLIFIER AND SWITCHING

P-CHANNEL — ENHANCEMENT

#### **MAXIMUM RATINGS**

Rating	Symbol	Value	Unit	
Drain-Source Voltage*	V <sub>DS</sub>	±35	Vdc	
Drain-Gate Voltage*	V <sub>DG</sub>	±50	Vdc	
Gate-Source Voltage*	Vgs	±50	Vdc	
Drain Current*	l <sub>D</sub>	30	mAdc	
Total Device Dissipation @ T <sub>A</sub> = 25°C Derate above 25°C*	PD	300 1.7	mW mW/°C	
Junction Temperature Range*	TJ	-65 to +175	°C	
Storage Channel Temperature Range*	T <sub>stg</sub>	-65 to +175	°C	

\*JEDEC Registered Limits

ON CHARACTERISTICS

ELECTRICAL CHARACTERISTICS (TA = 25°C unless otherwise noted.)

Characteristic	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS					
Drain-Source Breakdown Voltage (I <sub>D</sub> = -10 μAdc, V <sub>G</sub> = V <sub>S</sub> = 0)	V(BR)DSX	-35	<u> </u>		Vdc
Zero-Gate-Voltage Drain Current (VDS = -15 Vdc, VGS = 0) (VDS = -35 Vdc, VGS = 0)	IDSS			1.0 10	nAdc μAdc
Gate Reverse Current* (VGS = +25 Vdc, VDS = 0) (VGS = +50 Vdc, VDS = 0)	IGSS	1	_	+10 +10	pAdc nAdc
Input Resistance (VGS = -25 Vdc)	RGS	_	1 x 10+12		Ohms
Gate Source Voltage* (VDS = -15 Vdc, ID = -0.5 mAdc) 3N157 3N158	V <sub>GS</sub>	1.5 3.0	_	5.5 7.0	Vdc
Gate Forward Current* (VGS = -25 Vdc, VDS = 0) (VGS = -50 Vdc, VDS = 0) (VGS = -25 Vdc, VDS = 0, TA = +55°C) (VGS = -50 Vdc, VDS = 0, TA = +55°C)	lG(f)	=	1 1 1	- 10 - 1.0 - 10 - 1.0	pAdc nAdc nAdc μAdc

ON CHARACTERISTICS		,	<del>,</del>			
Gate Threshold Voltage*		VGS(Th)	1			Vdc
$(V_{DS} = -15 \text{ Vdc}, I_{D} = -10 \mu \text{Adc})$	3N157		- 1.5	_	-3.2	ļ
(4D2 = 10 4d0) (D 10 hr (m)	3N158	İ	-3.0	_	-5.0	
On-State Drain Current*		lD(on)	-5.0	_	_	mAdc
$(V_{DS} = -15 \text{ Vdc}, V_{GS} = -10 \text{ Vdc})$		L			L	l

Forward Transfer Admittance* (VDS = -15 Vdc, ID = -2.0 mAdc, f = 1.0 kHz)	lγfsl	1000	-	4000	μmhos
Output Admittance* (Vps = -15 Vdc, Ip = -2.0 mAdc, f = 1.0 kHz)	lyosl	_	_	60	μmhos
Input Capacitance* (Vps = -15 Vdc, Vgs = 0, f = 140 kHz)	C <sub>iss</sub>	_	_	5.0	pF
Reverse Transfer Capacitance* (VDS = -15 Vdc, VGS = 0, f = 140 kHz)	C <sub>rss</sub>	_		1.3	pF
Drain-Substrate Capacitance (VD(SUB) = -10 Vdc, f = 140 kHz)	C <sub>d(sub)</sub>	-	_	4.0	pF
Noise Voltage (R <sub>S</sub> = 0, BW = 1.0 Hz, V <sub>DS</sub> = -15 Vdc, I <sub>D</sub> = -2.0 mAdc, f = 100 Hz)	e <sub>n</sub>	·	300		NV/√Hz
VDS = -15 Vdc, ID = -2.0 IIIAdc, 1 - 100 Hz/ (RS = 0, BW = 1.0 Hz, VDS = -15 Vdc, ID = -2.0 mAdc, f = 1.0 kHz)			120	500	

\*JEDEC Registered Limits



## 6367254 MOTOROLA SC (XSTRS/R F)

# 3N157, 3N158

96D 82604

## T-37-25

D

FIGURE 1 - FORWARD TRANSCONDUCTANCE

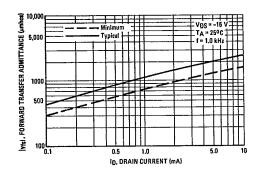


FIGURE 2 - OUTPUT TRANSCONDUCTANCE

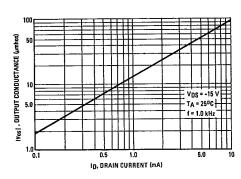


FIGURE 3 — FORWARD TRANSCONDUCTANCE versus TEMPERATURE

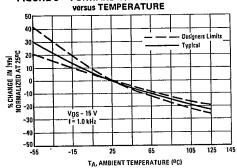


FIGURE 4 - BIAS CURVE

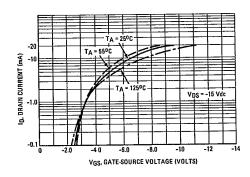


FIGURE 5 - "ON" DRAIN-SOURCE VOLTAGE

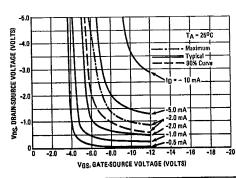
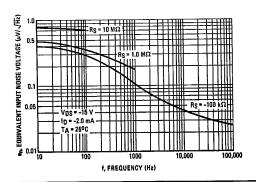


FIGURE 6 - EQUIVALENT INPUT NOISE VOLTAGE



MOTOROLA SMALL-SIGNAL SEMICONDUCTORS

### 6367254 MOTOROLA SC (XSTRS/R F)

96D 82605

3N157, 3N158

td1, TURN-ON DELAY TIME (ns)

-0.5

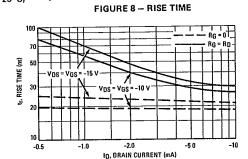
Vps = Vgs

T-37-25

### SWITCHING CHARACTERISTICS

 $(T_A = 25^{\circ}C)$ 

FIGURE 7 - TURN-ON DELAY TIME



ID, DRAIN CURRENT (mA) FIGURE 9 - TURN-OFF DELAY TIME

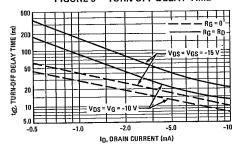


FIGURE 10 - FALL TIME

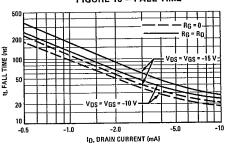
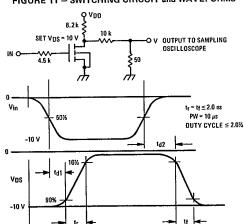


FIGURE 11 - SWITCHING CIRCUIT and WAVEFORMS



The switching characteristics shown above were measured in a test circuit similar to Figure 11. At the beginning of the switching interval, the gate voltage is at ground and the gate switching interval, the gate voltage is at ground and the gate source capacitance (Cgs • Crss • Crss) has no charge. The drain voltage is at VDD and thus the feedback capacitance (Crss) is charged to VDD. Similarly, the drain substrate capacitance (Cd(sub)) is charged to VDD since the substrate and source are connected to ground.

connected to ground. During the turn-on interval  $C_{gs}$  is charged to  $V_{GS}$  (the input voltage) through  $R_G$  (generator impedance) (Figure 12).  $C_{rss}$  must be discharged to  $V_{GS} \cdot V_{D(on)}$  through  $R_G$  and the parallel combination of the load resistor ( $R_D$ ) and the channel resistance ( $r_{ds}$ ). In addition,  $C_{d(sub)}$  is discharged to a low value ( $V_{D(on)}$ ) through  $R_D$  in parallel with  $r_{ds}$ . During turn-off this charge flow is reversed this charge flow is reversed.

Predicting turn-on time proves to be somewhat difficult since the channel resistance (rds) is a function of the gate source

voltage (VGS). As  $C_{\rm gs}$  becomes charged VGS is approaching V<sub>In</sub> and r<sub>ds</sub> decreases (see Figure 5) and since  $C_{\rm rss}$  and  $C_{\rm d}$ (sub) are charged through r<sub>ds</sub>, turn-on time is quite non-linear. If the charging time of  $C_{\rm gs}$  is short compared to that of  $C_{\rm rss}$  and  $C_{\rm d}$ (sub), then r<sub>ds</sub> (which is in parallel with R<sub>D</sub>) will be low compared to R<sub>D</sub> during the switching interval and will largely determine the turn-on time. On the other hand, during turnoff  $r_{ds}$  will be almost an open circuit requiring  $c_{rss}$  and  $c_{d(sub)}$  to be charged through RD and resulting in a turn-off time that is long compared to the turn-on time. This is especially noticeable for the curves where Rg • 0 and C<sub>gs</sub> is charged through the pulse generator impedance only. The switching curves shown with Rg • RD simulate the

switching behavior of cascaded stages where the driving source impedance is normally the same as the load impedance. The set of curves with Rg • 0 simulates a low source impedance drive such as might occur in complementary logic circuits.

FIGURE 12 - SWITCHING CIRCUIT with MOSFET **EQUIVALENT MODEL** 

